



# M I C A : Microscopic ChAracterization of functional and nanostructured materials

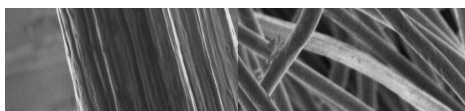
## WHAT WE OFFER : services and expertise

- Characterization / test / analysis performed by highly qualified UCLouvain members
- Microscopy characterization tools in the context of materials science, chemistry, solid-state physics, and (bio)nanotechnology



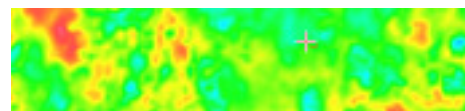
### Scanning Probe Microscopy (SPM)

- Surface topography in air or liquid
- Mechanical property analysis
- Electric property analysis
- Magnetic property analysis



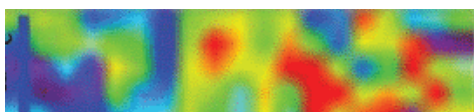
### Scanning Electron Microscopy (SEM)

- Micro- and nano- morphology
- STEM analysis
- Chemical mapping



### Infrared Spectrometer

- Infrared absorption spectrum
- Molecules structure
- Chemical mapping



### Raman Spectrometer

- Vibrational modes of molecules
- Chemical mapping



### Sample preparation tools

- Cryo-ultramicrotomy
- Sputters (carbon and metal)

## CONTACT

*Platform manager*

**Cécile D'Haese**

cecile.dhaese@uclouvain.be

+32(0)10/47.35.61

*Research logistician*

**Delphine Magnin**

delphine.magnin@uclouvain.be

+32(0)10/47.35.61

[www.uclouvain.be/mica](http://www.uclouvain.be/mica)

(1) AFM BRUKER Multimode – (2) AFM BRUKER Icon – (3) FEG-SEM JEOL 7600F – (4) IR THERMOFISHER Nicolet IN10 – (5) RAMAN THERMOFISHER DXR



Bâtiment Boltzmann  
Croix du Sud, 1 bte L7.04.02  
1348 Louvain-La-Neuve  
Belgium



**UCLouvain**

Avec le soutien de



LE FONDS SOCIAL EUROPÉEN ET LA WALLONIE  
INVESTISSENT DANS VOTRE AVENIR